

## Crystal Clock Oscillator

5V, True TTL

### Technical Data NCT Series

0 Level:

1 Level:

Load:





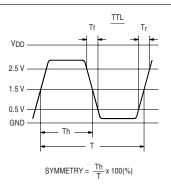
#### Description

A crystal controlled, hybrid oscillator circuit that produces a true TTL output characteristic at frequencies between 500 kHz and 66.6667 MHz. The device is mounted in a 14-pin DIP-compatible, all metal hermetic package. Physically and functionally interchangeable with all major manufacturers' devices.

#### **Applications & Features**

- Ideal for high performance RISC and CISC based products
- True TTL level for low EMI
- Broad frequency range to 66.6667 MHz

#### **Output Waveform**



Frequency Range:	500 kHz to 66.6667 MHz	
Frequency Stability:	$\pm 25$ , $\pm 50$ or $\pm 100$ ppm over all conditions: calibration tolerance, operating temperature, input voltage change, load change, aging, shock and vibration.	
Temperature Range:		
Operating:	0°C to +70°C or -40 to +85°C(limited frequencies)	
Storage:	-55°C to +125°C	
Supply Voltage:	+5 VDC ±10%	
Supply Current:	Max @ 25°C	Max over Temperature
500 kHz to 20 MHz:	30mA	40mA
20+ to 66.6667 MHz:	65mA	70mA
TTL Output:		
Symmetry:	40/60% max @ 1.5 VDC level	
Rise & Fall Times:	8ns max: 500 kHz to 25 MHz	

6ns max: 25+ to 66.6667 MHz

1 to 10 TTL gates (1.6mA per gate)

0.5V max

2.5V min

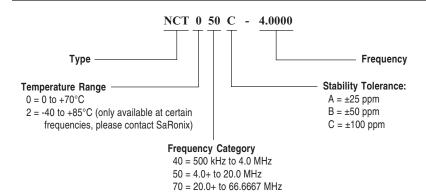
#### Mechanical:

Shock: MIL-STD-883, Method 2002, Condition B
Solderability: MIL-STD-883, Method 2003
Terminal Strength: MIL-STD-883, Method 2004, Condition B2
Vibration: MIL-STD-883, Method 2007, Condition A
MIL-STD-202, Method 215
Resistance to Soldering Heat: MIL-STD-202, Method 210, Condition A, B or C

#### **Environmental:**

Gross Leak Test: MIL-STD-883, Method 1014, Condition C
Fine Leak Test: MIL-STD-883, Method 1014, Condition A
Thermal Shock: MIL-STD-883, Method 1011, Condition A
Moisture Resistance: MIL-STD-883, Method 1004

#### Part Numbering Guide:



DS-129 REV E

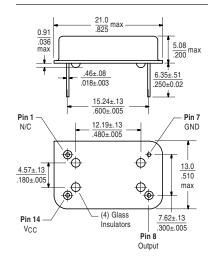


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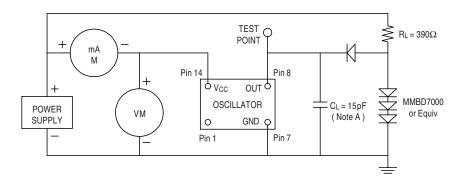
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#### **Package Details**

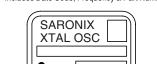


### **Test Circuit**



NOTE A: C<sub>L</sub> Includes probe and fixture capacitance

# Standard Marking Format \* Includes Date Code, Frequency & Part Number



Denotes Pin 1

Scale: None (Dimensions in  $\frac{mm}{inches}$ )

All specifications are subject to change without notice.

DS-129 REV E

<sup>\*</sup> Exact locations of items may vary